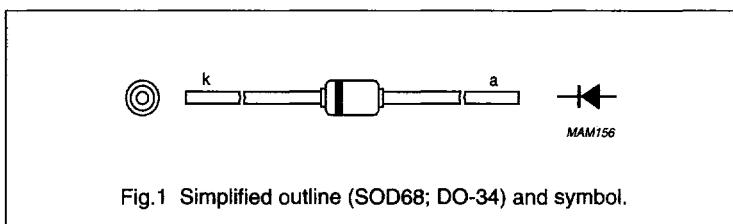


Low-leakage diode**BAS45A****FEATURES**

- Continuous reverse voltage:
max. 125 V
- Repetitive peak forward current:
max. 625 mA
- Low reverse current: max. 1 nA
- Switching time: typ. 1.5 μ s.

DESCRIPTION

Epitaxial medium-speed switching diode with a low leakage current in a hermetically-sealed glass SOD68 (DO-34) package.

**APPLICATION**

- Low leakage current applications.

Fig.1 Simplified outline (SOD68; DO-34) and symbol.

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

| SYMBOL | PARAMETER | CONDITIONS | MIN. | MAX. | UNIT |
|-----------|-------------------------------------|---|------|------|------|
| V_{RRM} | repetitive peak reverse voltage | | — | 125 | V |
| V_R | continuous reverse voltage | | — | 125 | V |
| I_F | continuous forward current | see Fig.2; note 1 | — | 250 | mA |
| I_{FRM} | repetitive peak forward current | | — | 625 | mA |
| I_{FSM} | non-repetitive peak forward current | square wave; $T_j = 25^\circ\text{C}$ prior to surge; see Fig.4 $t_p = 1 \mu\text{s}$ $t_p = 1 \text{ ms}$ $t_p = 1 \text{ s}$ | — | 4 | A |
| P_{tot} | total power dissipation | $T_{amb} = 25^\circ\text{C}$ | — | 300 | mW |
| T_{stg} | storage temperature | | -65 | +175 | °C |
| T_j | junction temperature | | — | 175 | °C |

Note

1. Device mounted on a printed-circuit board without metallization pad.

Low-leakage diode

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ELECTRICAL CHARACTERISTICS

 $T_j = 25^\circ\text{C}$ unless otherwise specified.

| SYMBOL | PARAMETER | CONDITIONS | TYP. | MAX. | UNIT |
|----------|-----------------------|---|------|------|---------------|
| V_F | forward voltage | see Fig.3 $I_F = 1 \text{ mA}$ $I_F = 10 \text{ mA}$ $I_F = 100 \text{ mA}$ | — | 780 | mV |
| I_R | reverse current | see Fig.5 $V_R = 125 \text{ V}; E_{\max} = 100 \text{ lx}$ $V_R = 30 \text{ V}; T_j = 125^\circ\text{C}; E_{\max} = 100 \text{ lx}$ $V_R = 125 \text{ V}; T_j = 125^\circ\text{C}; E_{\max} = 100 \text{ lx}$ $V_R = 125 \text{ V}; T_j = 150^\circ\text{C}; E_{\max} = 100 \text{ lx}$ | — | 1 | nA |
| C_d | diode capacitance | $f = 1 \text{ MHz}; V_R = 0$; see Fig.6 | — | 4 | pF |
| t_{rr} | reverse recovery time | when switched from $I_F = 10 \text{ mA}$ to $I_R = 10 \text{ mA}; R_L = 100 \Omega$; measured at $I_R = 1 \text{ mA}$; see Fig.7 | 1.5 | — | μs |

THERMAL CHARACTERISTICS

| SYMBOL | PARAMETER | CONDITIONS | VALUE | UNIT |
|----------------------|---|---------------------------|-------|------|
| $R_{th j\text{-tp}}$ | thermal resistance from junction to tie-point | 8 mm from the body | 300 | K/W |
| $R_{th j\text{-a}}$ | thermal resistance from junction to ambient | lead length 10 mm; note 1 | 500 | K/W |

Note

1. Device mounted on a printed-circuit board without metallization pad.

Low-leakage diode

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GRAPHICAL DATA

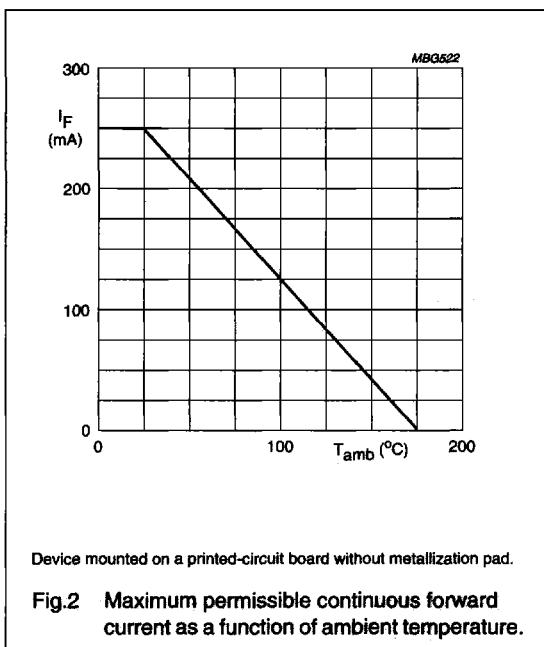


Fig.2 Maximum permissible continuous forward current as a function of ambient temperature.

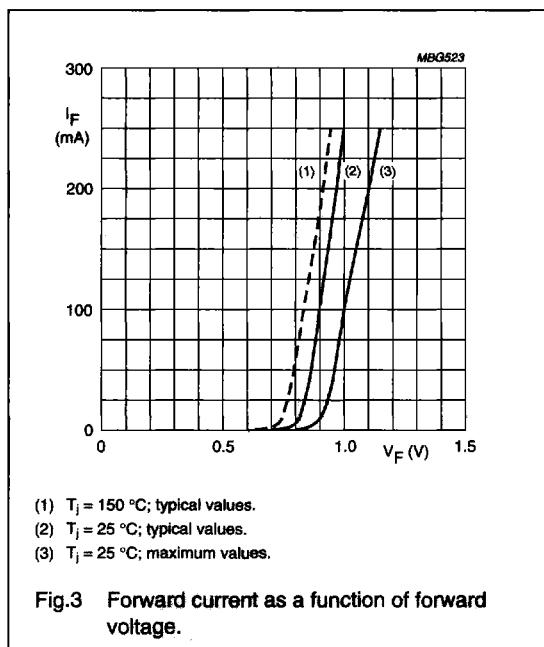


Fig.3 Forward current as a function of forward voltage.

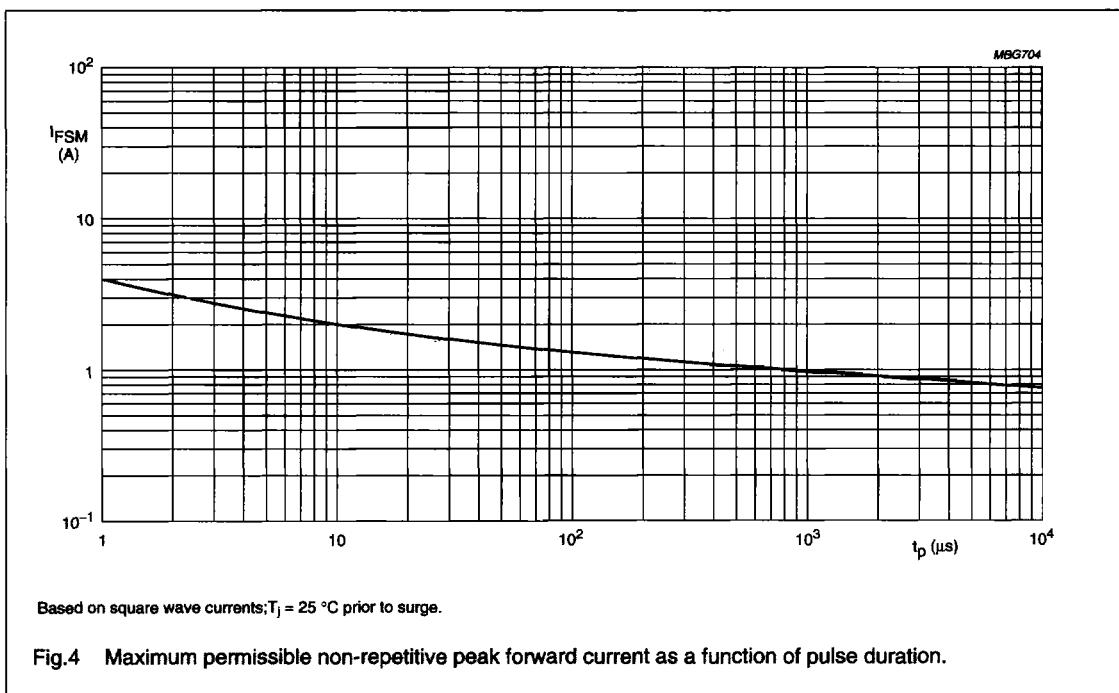


Fig.4 Maximum permissible non-repetitive peak forward current as a function of pulse duration.

Low-leakage diode

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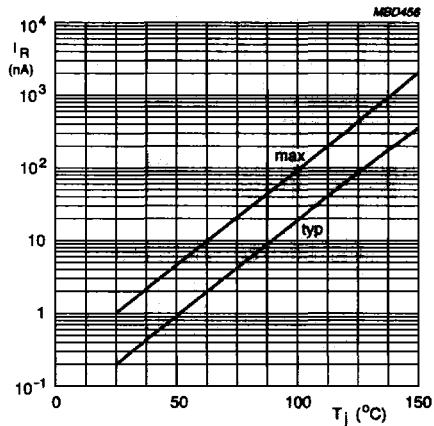
 $V_R = 125$ V.

Fig.5 Reverse current as a function of junction temperature.

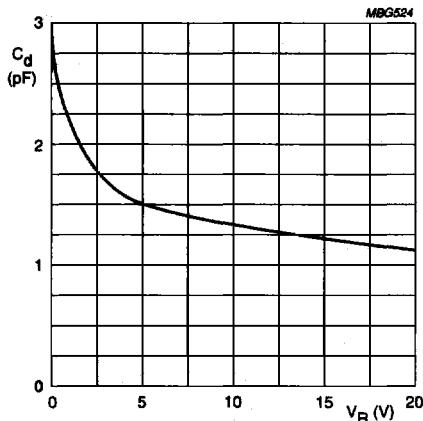
 $f = 1$ MHz; $T_j = 25$ $^{\circ}$ C.

Fig.6 Diode capacitance as a function of reverse voltage; typical values.

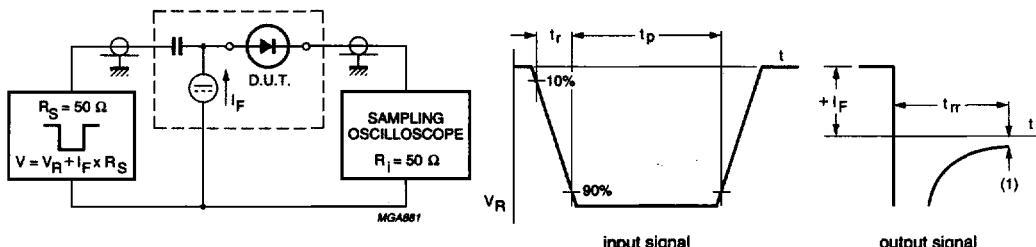


Fig.7 Reverse recovery time test circuit and waveforms.